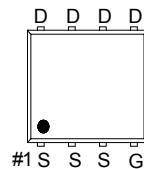
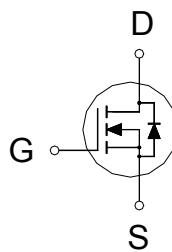


NIKO-SEM
**N-Channel Enhancement Mode
Field Effect Transistor**
PA110BEA
PDFN 3x3P
Halogen-Free & Lead-Free
PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
100V	105mΩ	8.5A


G. GATE
D. DRAIN
S. SOURCE

100% UIS Tested
100% Rg Tested
ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		V_{DS}	100	V
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current	$T_C = 25^\circ\text{C}$	I_D	8.5	A
	$T_C = 100^\circ\text{C}$		5.4	
Pulsed Drain Current ¹		I_{DM}	15	
Continuous Drain Current	$T_A = 25^\circ\text{C}$	I_D	3.5	W
	$T_A = 70^\circ\text{C}$		2.8	
Avalanche Current		I_{AS}	5.9	
Avalanche Energy	$L = 1\text{mH}$	E_{AS}	17.5	mJ
Power Dissipation	$T_C = 25^\circ\text{C}$	P_D	18	W
	$T_C = 100^\circ\text{C}$		7.3	
Power Dissipation ³	$T_A = 25^\circ\text{C}$	P_D	3.1	W
	$T_A = 70^\circ\text{C}$		2	
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE		SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient ²	$t \leq 10\text{s}$	$R_{\theta JA}$		40	°C / W
Junction-to-Ambient ²	Steady-State	$R_{\theta JA}$		68	
Junction-to-Case	Steady-State	$R_{\theta JC}$		6.8	

¹Pulse width limited by maximum junction temperature.

²The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$.

³The Power dissipation is based on $R_{\theta JA} t \leq 10\text{s}$ value.

NIKO-SEM**N-Channel Enhancement Mode
Field Effect Transistor****PA110BEA
PDFN 3x3P
Halogen-Free & Lead-Free****ELECTRICAL CHARACTERISTICS (T_J = 25 °C, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0V, I _D = 250µA	100			V
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250µA	1	1.8	3	
Gate-Body Leakage	I _{GSS}	V _{DS} = 0V, V _{GS} = ±20V			±100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 80V, V _{GS} = 0V			1	
		V _{DS} = 80V, V _{GS} = 0V, T _J = 55 °C			10	µA
Drain-Source On-State Resistance ¹	R _{DS(ON)}	V _{GS} = 4.5V, I _D = 6A		85	120	
		V _{GS} = 10V, I _D = 6A		80	105	mΩ
Forward Transconductance ¹	g _{fs}	V _{DS} = 5V, I _D = 6A		25		s
DYNAMIC						
Input Capacitance	C _{iss}	V _{GS} = 0V, V _{DS} = 25V, f = 1MHz		617		
Output Capacitance	C _{oss}			52		pF
Reverse Transfer Capacitance	C _{rss}			29		
Gate Resistance	R _g	V _{GS} = 0V, V _{DS} = 0V, f = 1MHz		1.5		Ω
Total Gate Charge ²	Q _g	V _{GS} = 10V		13		
		V _{GS} = 4.5V		7.5		
Gate-Source Charge ²	Q _{gs}	V _{DS} = 50V , V _{GS} = 10V, I _D = 6A		1.7		nC
Gate-Drain Charge ²	Q _{gd}			4.1		
Turn-On Delay Time ²	t _{d(on)}			9		
Rise Time ²	t _r			30		
Turn-Off Delay Time ²	t _{d(off)}	V _{DS} = 50V , I _D ≈ 6A, V _{GS} = 10V, R _{GEN} = 6Ω		23		nS
Fall Time ²	t _f			42		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T_J = 25 °C)						
Continuous Current ³	I _S				8.5	A
Forward Voltage ¹	V _{SD}	I _F = 6A, V _{GS} = 0V			1.4	V
Reverse Recovery Time	t _{rr}	I _F = 6A, dI _F /dt = 100A / µs		21		nS
Reverse Recovery Charge	Q _{rr}			12		nC

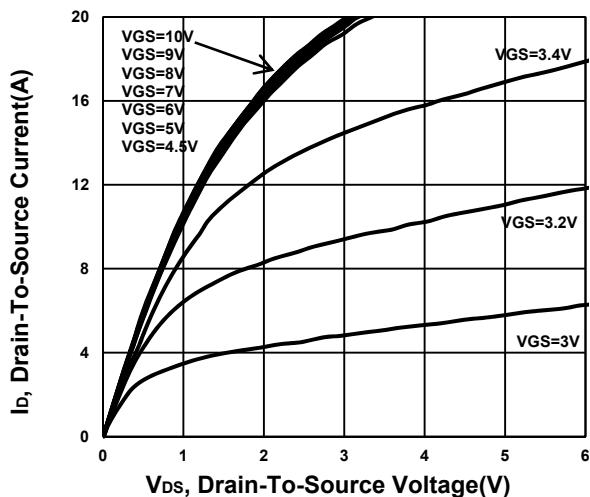
¹Pulse test : Pulse Width ≤ 300 µsec, Duty Cycle ≤ 2%.²Independent of operating temperature.

NIKO-SEM

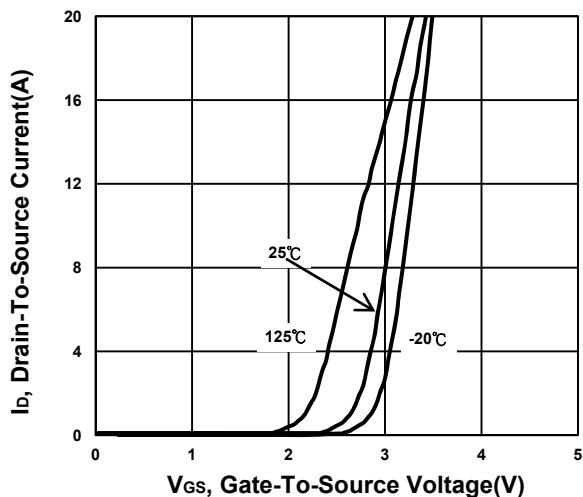
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Field Effect Transistor**

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Halogen-Free & Lead-Free

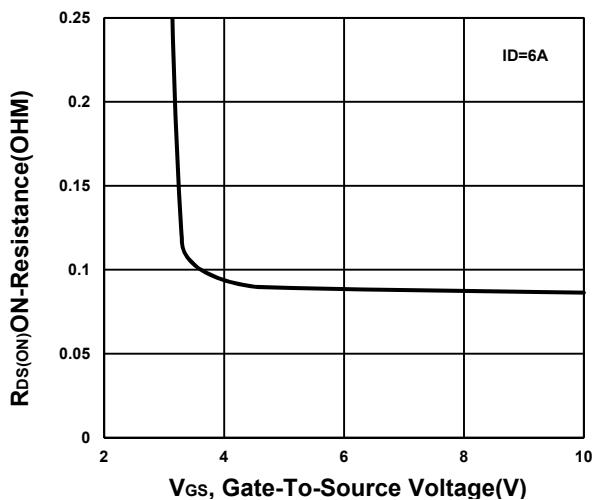
Output Characteristics



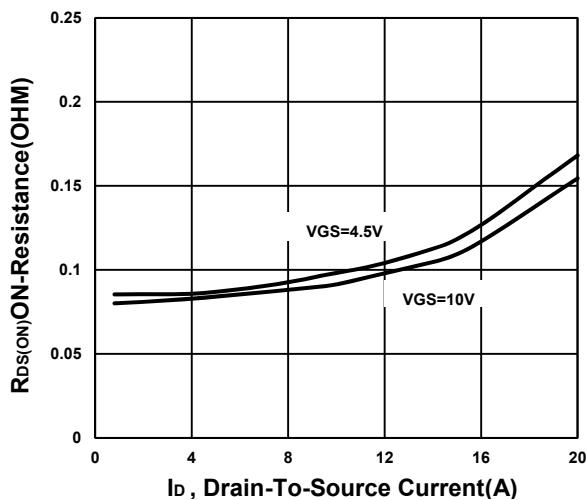
Transfer Characteristics



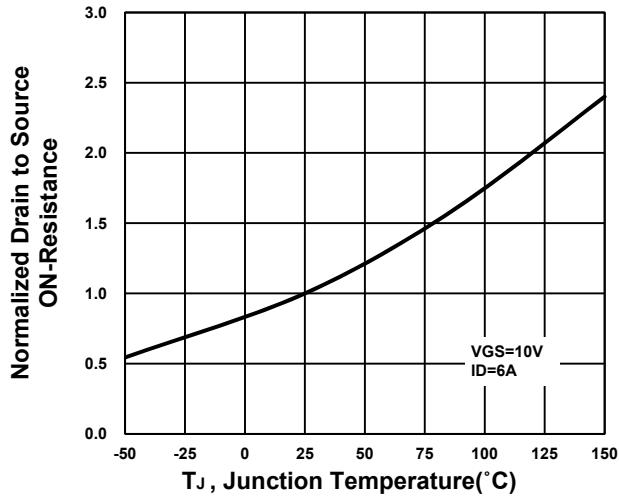
On-Resistance VS Gate-To-Source



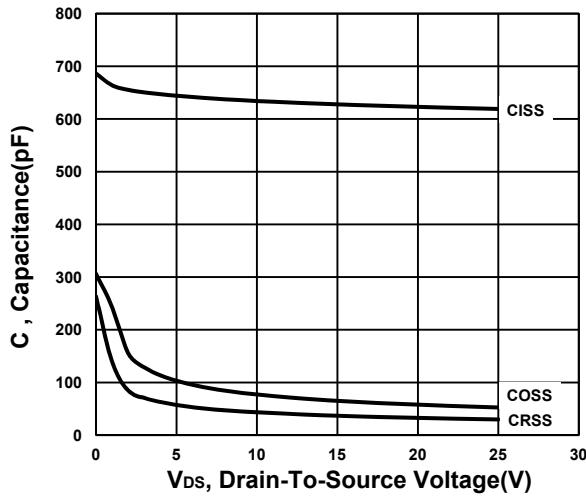
On-Resistance VS Drain Current

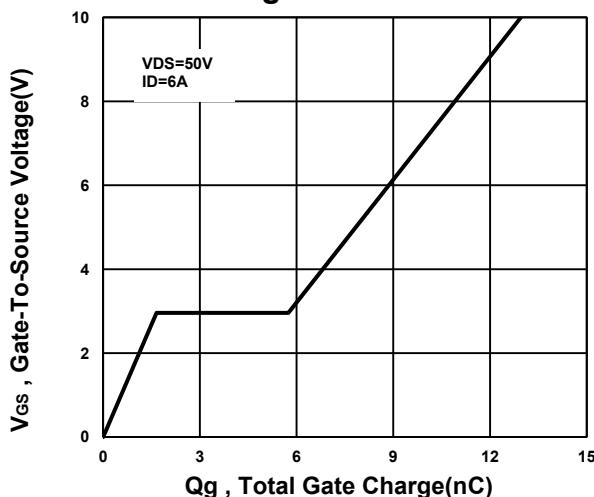
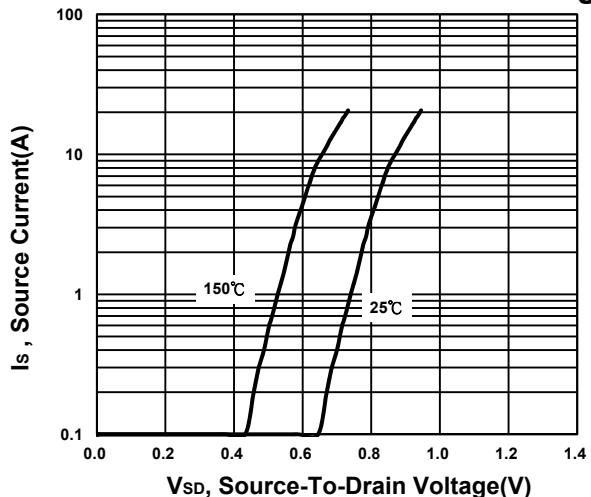
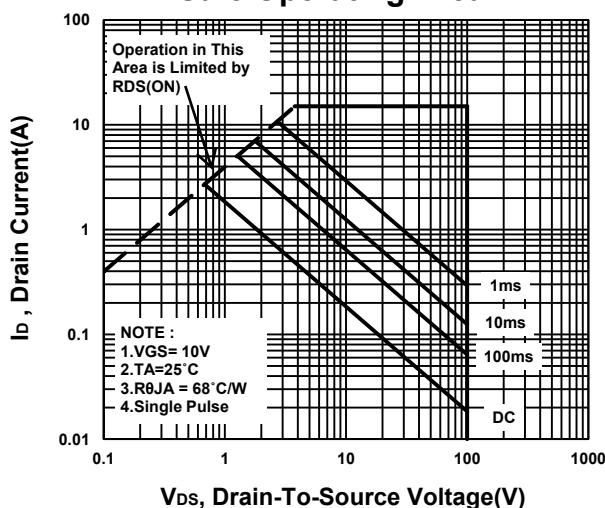
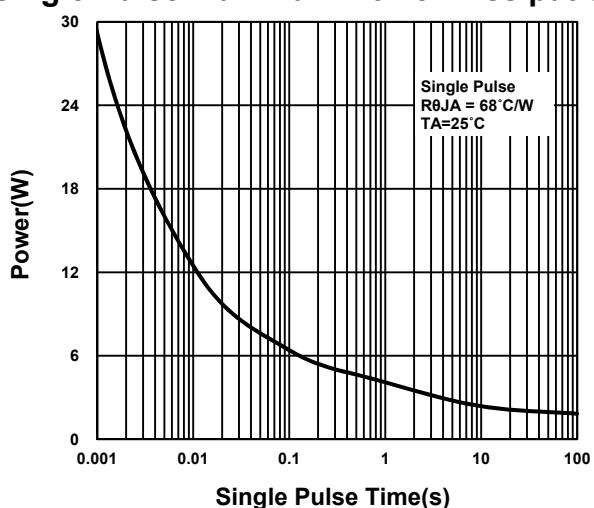


On-Resistance VS Temperature



Capacitance Characteristic



NIKO-SEM**N-Channel Enhancement Mode
Field Effect Transistor****PA110BEA
PDFN 3x3P
Halogen-Free & Lead-Free****Gate charge Characteristics****Source-Drain Diode Forward Voltage****Safe Operating Area****Single Pulse Maximum Power Dissipation****Transient Thermal Response Curve**